

**Search Notes**

Application/Control No.

10/757,095

Examiner

John J. Park

Applicant(s)/Patent under  
Reexamination

ATTIA ET AL.

Art Unit

2876

**SEARCHED**

Class	Subclass	Date	Examiner
235	462.46		
235	462.25		
235	462.01		
235	462.07		
235	462.11		
235	383		
235	385		
382	289		
349	117		
455	422	2/18/2005	JP

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST		
Text Search		
Consulted with S. Paik in AU 2876	2/18/2005	JP